

INTERNATIONAL STANDARD



**Electrical equipment for measurement, control and laboratory use –
EMC requirements –
Part 2-1: Particular requirements – Test configurations, operational conditions
and performance criteria for sensitive test and measurement equipment for
EMC unprotected applications**



THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2020 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester. If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
info@iec.ch
www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigendum or an amendment might have been published.

IEC publications search - webstore.iec.ch/advsearchform

The advanced search enables to find IEC publications by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, replaced and withdrawn publications.

IEC Just Published - webstore.iec.ch/justpublished

Stay up to date on all new IEC publications. Just Published details all new publications released. Available online and once a month by email.

IEC Customer Service Centre - webstore.iec.ch/csc

If you wish to give us your feedback on this publication or need further assistance, please contact the Customer Service Centre: sales@iec.ch.

Electropedia - www.electropedia.org

The world's leading online dictionary on electrotechnology, containing more than 22 000 terminological entries in English and French, with equivalent terms in 16 additional languages. Also known as the International Electrotechnical Vocabulary (IEV) online.

IEC Glossary - std.iec.ch/glossary

67 000 electrotechnical terminology entries in English and French extracted from the Terms and Definitions clause of IEC publications issued since 2002. Some entries have been collected from earlier publications of IEC TC 37, 77, 86 and CISPR.

IECNORM.COM : Click to view the full PDF IEC 60322-1:2020 PLV

INTERNATIONAL STANDARD



**Electrical equipment for measurement, control and laboratory use –
EMC requirements –
Part 2-1: Particular requirements – Test configurations, operational conditions
and performance criteria for sensitive test and measurement equipment for
EMC unprotected applications**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

ICS 17.220.20; 25.040.40; 33.100.20

ISBN 978-2-8322-8989-1

Warning! Make sure that you obtained this publication from an authorized distributor.

CONTENTS

FOREWORD	3
1 Scope	5
2 Normative references	5
3 Terms and definitions	5
4 General	5
5 EMC test plan	6
5.1 General	6
5.2 Configuration of EUT during testing	6
5.3 Operation conditions of EUT during testing	6
5.4 Specification of FUNCTIONAL PERFORMANCE	7
5.5 Test description	7
6 Immunity requirements	7
6.1 Conditions during the tests	7
6.2 Immunity test requirements	7
6.3 Random aspects	7
6.4 Performance criteria	7
7 Emission requirements	7
8 Test results and test report	7
9 Instructions for use	8
Annex A (normative) Immunity test requirements for PORTABLE TEST AND MEASUREMENT EQUIPMENT powered by battery or from the circuit being measured	9
Annex B (informative) Guide for analysis and assessment for electromagnetic compatibility	10

IECNORM.COM : Click to view the full PDF of IEC 61326-2-1:2020 RLV

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**ELECTRICAL EQUIPMENT FOR MEASUREMENT,
CONTROL AND LABORATORY USE –
EMC REQUIREMENTS –****Part 2-1: Particular requirements –
Test configurations, operational conditions and performance
criteria for sensitive test and measurement equipment
for EMC unprotected applications**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

This redline version of the official IEC Standard allows the user to identify the changes made to the previous edition. A vertical bar appears in the margin wherever a change has been made. Additions are in green text, deletions are in strikethrough red text.

International Standard IEC 61326-2-1 has been prepared by subcommittee 65A: System aspects, of IEC technical committee 65: Industrial-process measurement, control and automation.

This third edition cancels and replaces the second edition published in 2012. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- update with respect to IEC 61326-1:2020.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
65A/976/FDIS	65A/987/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

This part of IEC 61326 is to be used in conjunction with IEC 61326-1:2020 and follows the same numbering of clauses, subclauses, tables and figures.

When a particular subclause of IEC 61326-1 is not mentioned in this part, that subclause applies as far as is reasonable. When this standard states “addition”, “modification” or “replacement”, the relevant text in IEC 61326-1 is to be adapted accordingly.

NOTE The following numbering system is used:

- subclauses, tables and figures that are numbered starting from 101 are additional to those in IEC 61326-1;
- unless notes are in a new subclause or involve notes in IEC 61326-1, they are numbered starting from 101 including those in a replaced clause or subclause;
- additional annexes are lettered AA, BB, etc.

A list of all parts of IEC 61326 series, under the general title *Electrical equipment for measurement, control and laboratory use – EMC requirements*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL AND LABORATORY USE – EMC REQUIREMENTS –

Part 2-1: Particular requirements – Test configurations, operational conditions and performance criteria for sensitive test and measurement equipment for EMC unprotected applications

1 Scope

In addition to the scope of IEC 61326-1, this part of IEC 61326 specifies more detailed test configurations, operational conditions and performance criteria for equipment with test and measurement circuits (~~both~~ internal ~~and~~ or, external to the equipment, ~~or both~~) that are not EMC protected for operational and/or functional reasons, as specified by the manufacturer.

The manufacturer specifies the environment for which the product is intended to be used and selects the appropriate test level specifications of IEC 61326-1:2020.

NOTE Examples of equipment include, but are not limited to, oscilloscopes, logic analysers, spectrum analysers, network analysers, analogue instruments, digital multimeters (DMM) and board test systems.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

Clause 2 of IEC 61326-1:2020 applies except as follows:

Addition:

IEC 61326-1:2012/2020, *Electrical equipment for measurement, control and laboratory use – EMC requirements – Part 1: General requirements*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 61326-1:2020 and IEC 60050-161 apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

4 General

Clause 4 of IEC 61326-1:2020 applies.

5 EMC test plan

5.1 General

Subclause 5.1 of IEC 61326-1:2020 applies.

5.2 Configuration of EUT during testing

Subclause 5.2 of IEC 61326-1:2020 applies, except as follows:

Addition:

5.2.4.101 I/O ports for test and measurement purposes

Test and measurement input ports shall be ~~capped and shorted~~ covered and terminated with an appropriate impedance unless this leads to an operating condition unsuitable for measuring the emission and immunity performance of the product. If an input signal is needed, an appropriate input signal shall be applied using test leads or probes as specified by the manufacturer.

Test and measurement output ports not needed to evaluate the essential functions of the EUT shall be ~~capped~~ covered and/or terminated.

Electrostatic discharges shall be applied to the ~~housing shield~~ mated connector or the shield of the unmated port, but not to the inner pins of shielded port or cable connectors.

Examples include but are not limited to: USB, BNC, D-subminiature, ~~IEEE 488 (IEC 60488)~~, GPIB, RS232 and IEEE 1284-B (parallel printer port), etc.

NOTE 1 Probes and/or test leads not used to apply an input signal during test to the test and measurement ports do not need to be connected. Such test leads can vary substantially from one application to another and are often connected to equipment that has the covers removed and ~~may~~ can be in various stages of disassembly to provide access to test points inside. Connected test leads ~~may~~ could increase emissions and/or reduce immunity in certain applications.

NOTE 2 ~~Capped~~ Covered means locally covered with a screen or shield.

5.3 Operation conditions of EUT during testing

Subclause 5.3 of IEC 61326-1:2020 applies, except as follows:

Addition:

5.3.101 Operational conditions

When both battery and ~~a-c~~ mains options are available, both modes of operation shall comply.

5.3.102 Oscilloscopes

The oscilloscope ports shall be set for maximum sweep speed, maximum sensitivity and continuous acquisition mode unless other modes are known to provide worst-case emission or immunity results within normal applications.

5.3.103 Logic analysers

The logic analyser shall be set for data analysis modes during emission measurement and continuous data acquisition mode during immunity testing unless other modes are known to provide worst-case emission or immunity results within normal applications.

5.3.104 Digital multimeters (DMM)

Typical set-ups include: peak detect, maximum sensitivity (usually auto-range, if available, will suffice) and continuous acquisition mode.

5.3.105 Other equipment

For equipment not mentioned in 5.3.102 to 5.3.104, the following philosophy shall apply.

A selection of representative operation modes shall be made, taking into account that not all functions, but only the most typical functions of the equipment can be tested. The estimated worst-case operating modes for normal application shall be selected.

5.4 Specification of FUNCTIONAL PERFORMANCE

Subclause 5.4 of IEC 61326-1:2020 applies.

5.5 Test description

Subclause 5.5 of IEC 61326-1:2020 applies.

6 Immunity requirements

6.1 Conditions during the tests

Subclause 6.1 of IEC 61326-1:2020 applies.

6.2 Immunity test requirements

Subclause 6.2 of IEC 61326-1:2020 applies.

6.3 Random aspects

Subclause 6.3 of IEC 61326-1:2020 applies.

6.4 Performance criteria

Subclause 6.4 of IEC 61326-1:2020 applies, except as follows:

Addition:

6.4.101 Tests with transient electromagnetic phenomenon

During testing with transient electromagnetic phenomena that are assigned to performance criteria B in Table 1, 2 or 3 of IEC 61326-1:2020, the EUT may have temporary degradation or loss of function or performance which is self-recovering. Self-recovery times greater than 10 s shall be specified by the manufacturer in the equipment documentation for the user. Trigger functions need not be evaluated. No change in actual operating state or loss of stored data is allowed.

7 Emission requirements

Clause 7 of IEC 61326-1:2020 applies.

8 Test results and test report

Clause 8 of IEC 61326-1:2020 applies.

9 Instructions for use

Clause 9 of IEC 61326-1:2020 applies, except as follows:

Addition:

9.101 Additional instructions

The manufacturer shall give information that the equipment ~~may~~ **might** not meet the immunity requirements of this document when test leads and/or test probes are connected and shall give guidance **on** how to use test leads and/or test probes to minimize the impact of disturbances.

IECNORM.COM : Click to view the full PDF of IEC 61326-2-1:2020 RLV

Annex A
(normative)

**Immunity test requirements for PORTABLE TEST AND MEASUREMENT
EQUIPMENT powered by battery or from the circuit being measured**

Annex A of IEC 61326-1:2020 does not apply.

IECNORM.COM : Click to view the full PDF of IEC 61326-2-1:2020 RLV

Annex B
(informative)

Guide for analysis and assessment for electromagnetic compatibility

Annex B of IEC 61326-1:2020 applies.

IECNORM.COM : Click to view the full PDF of IEC 61326-2-1:2020 RLV

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Electrical equipment for measurement, control and laboratory use –
EMC requirements –**

**Part 2-1: Particular requirements – Test configurations, operational conditions
and performance criteria for sensitive test and measurement equipment for
EMC unprotected applications**

**Matériel électrique de mesure, de commande et de laboratoire –
Exigences relatives à la CEM –**

**Partie 2-1: Exigences particulières – Configurations d'essai, conditions
fonctionnelles et critères de performance pour essai de sensibilité et matériel de
mesure pour les applications non protégées de la CEM**

CONTENTS

FOREWORD	3
1 Scope	5
2 Normative references	5
3 Terms and definitions	5
4 General	5
5 EMC test plan	6
5.1 General	6
5.2 Configuration of EUT during testing	6
5.3 Operation conditions of EUT during testing	6
5.4 Specification of FUNCTIONAL PERFORMANCE	7
5.5 Test description	7
6 Immunity requirements	7
6.1 Conditions during the tests	7
6.2 Immunity test requirements	7
6.3 Random aspects	7
6.4 Performance criteria	7
7 Emission requirements	7
8 Test results and test report	7
9 Instructions for use	8
Annex A (normative) Immunity test requirements for PORTABLE TEST AND MEASUREMENT EQUIPMENT powered by battery or from the circuit being measured	9
Annex B (informative) Guide for analysis and assessment for electromagnetic compatibility	10

IECNORM.COM : Click to view the full PDF of IEC 61326-2-1:2020 PLV

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**ELECTRICAL EQUIPMENT FOR MEASUREMENT,
CONTROL AND LABORATORY USE –
EMC REQUIREMENTS –****Part 2-1: Particular requirements –
Test configurations, operational conditions and performance
criteria for sensitive test and measurement equipment
for EMC unprotected applications**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 61326-2-1 has been prepared by subcommittee 65A: System aspects, of IEC technical committee 65: Industrial-process measurement, control and automation.

This third edition cancels and replaces the second edition published in 2012. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- update with respect to IEC 61326-1:2020.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
65A/976/FDIS	65A/987/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

This part of IEC 61326 is to be used in conjunction with IEC 61326-1:2020 and follows the same numbering of clauses, subclauses, tables and figures.

When a particular subclause of IEC 61326-1 is not mentioned in this part, that subclause applies as far as is reasonable. When this standard states “addition”, “modification” or “replacement”, the relevant text in IEC 61326-1 is to be adapted accordingly.

NOTE The following numbering system is used:

- subclauses, tables and figures that are numbered starting from 101 are additional to those in IEC 61326-1;
- unless notes are in a new subclause or involve notes in IEC 61326-1, they are numbered starting from 101 including those in a replaced clause or subclause;
- additional annexes are lettered AA, BB, etc.

A list of all parts of IEC 61326 series, under the general title *Electrical equipment for measurement, control and laboratory use – EMC requirements*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL AND LABORATORY USE – EMC REQUIREMENTS –

Part 2-1: Particular requirements – Test configurations, operational conditions and performance criteria for sensitive test and measurement equipment for EMC unprotected applications

1 Scope

In addition to the scope of IEC 61326-1, this part of IEC 61326 specifies more detailed test configurations, operational conditions and performance criteria for equipment with test and measurement circuits (internal or, external to the equipment, or both) that are not EMC protected for operational and/or functional reasons, as specified by the manufacturer.

The manufacturer specifies the environment for which the product is intended to be used and selects the appropriate test level specifications of IEC 61326-1:2020.

NOTE Examples of equipment include, but are not limited to, oscilloscopes, logic analysers, spectrum analysers, network analysers, analogue instruments, digital multimeters (DMM) and board test systems.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

Clause 2 of IEC 61326-1:2020 applies except as follows:

Addition:

IEC 61326-1:2020, *Electrical equipment for measurement, control and laboratory use – EMC requirements – Part 1: General requirements*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 61326-1:2020 and IEC 60050-161 apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

4 General

Clause 4 of IEC 61326-1:2020 applies.

5 EMC test plan

5.1 General

Subclause 5.1 of IEC 61326-1:2020 applies.

5.2 Configuration of EUT during testing

Subclause 5.2 of IEC 61326-1:2020 applies, except as follows:

Addition:

5.2.4.101 I/O ports for test and measurement purposes

Test and measurement input ports shall be covered and terminated with an appropriate impedance unless this leads to an operating condition unsuitable for measuring the emission and immunity performance of the product. If an input signal is needed, an appropriate input signal shall be applied using test leads or probes as specified by the manufacturer.

Test and measurement output ports not needed to evaluate the essential functions of the EUT shall be covered and/or terminated.

Electrostatic discharges shall be applied to the mated connector or the shield of the unmated port, but not to the inner pins of shielded port or cable connectors.

Examples include but are not limited to: USB, BNC, D-subminiature, GPIB, RS232 and IEEE 1284-B (parallel printer port), etc.

NOTE 1 Probes and/or test leads not used to apply an input signal during test to the test and measurement ports do not need to be connected. Such test leads can vary substantially from one application to another and are often connected to equipment that has the covers removed and can be in various stages of disassembly to provide access to test points inside. Connected test leads could increase emissions and/or reduce immunity in certain applications.

NOTE 2 Covered means locally covered with a screen or shield.

5.3 Operation conditions of EUT during testing

Subclause 5.3 of IEC 61326-1:2020 applies, except as follows:

Addition:

5.3.101 Operational conditions

When both battery and mains options are available, both modes of operation shall comply.

5.3.102 Oscilloscopes

The oscilloscope ports shall be set for maximum sweep speed, maximum sensitivity and continuous acquisition mode unless other modes are known to provide worst-case emission or immunity results within normal applications.

5.3.103 Logic analysers

The logic analyser shall be set for data analysis modes during emission measurement and continuous data acquisition mode during immunity testing unless other modes are known to provide worst-case emission or immunity results within normal applications.

5.3.104 Digital multimeters (DMM)

Typical set-ups include: peak detect, maximum sensitivity (usually auto-range, if available, will suffice) and continuous acquisition mode.

5.3.105 Other equipment

For equipment not mentioned in 5.3.102 to 5.3.104, the following philosophy shall apply.

A selection of representative operation modes shall be made, taking into account that not all functions, but only the most typical functions of the equipment can be tested. The estimated worst-case operating modes for normal application shall be selected.

5.4 Specification of FUNCTIONAL PERFORMANCE

Subclause 5.4 of IEC 61326-1:2020 applies.

5.5 Test description

Subclause 5.5 of IEC 61326-1:2020 applies.

6 Immunity requirements

6.1 Conditions during the tests

Subclause 6.1 of IEC 61326-1:2020 applies.

6.2 Immunity test requirements

Subclause 6.2 of IEC 61326-1:2020 applies.

6.3 Random aspects

Subclause 6.3 of IEC 61326-1:2020 applies.

6.4 Performance criteria

Subclause 6.4 of IEC 61326-1:2020 applies, except as follows:

Addition:

6.4.101 Tests with transient electromagnetic phenomenon

During testing with transient electromagnetic phenomena that are assigned to performance criteria B in Table 1, 2 or 3 of IEC 61326-1:2020, the EUT may have temporary degradation or loss of function or performance which is self-recovering. Self-recovery times greater than 10 s shall be specified by the manufacturer in the equipment documentation for the user. Trigger functions need not be evaluated. No change in actual operating state or loss of stored data is allowed.

7 Emission requirements

Clause 7 of IEC 61326-1:2020 applies.

8 Test results and test report

Clause 8 of IEC 61326-1:2020 applies.

9 Instructions for use

Clause 9 of IEC 61326-1:2020 applies, except as follows:

Addition:

9.101 Additional instructions

The manufacturer shall give information that the equipment might not meet the immunity requirements of this document when test leads and/or test probes are connected and shall give guidance on how to use test leads and/or test probes to minimize the impact of disturbances.

IECNORM.COM : Click to view the full PDF of IEC 61326-2-1:2020 RLV

Annex A
(normative)

**Immunity test requirements for PORTABLE TEST AND MEASUREMENT
EQUIPMENT powered by battery or from the circuit being measured**

Annex A of IEC 61326-1:2020 does not apply.

IECNORM.COM : Click to view the full PDF of IEC 61326-2-1:2020 RLV

Annex B
(informative)

Guide for analysis and assessment for electromagnetic compatibility

Annex B of IEC 61326-1:2020 applies.

IECNORM.COM : Click to view the full PDF of IEC 61326-2-1:2020 RLV

IECNORM.COM : Click to view the full PDF of IEC 61326-2-1:2020 RLV

SOMMAIRE

AVANT-PROPOS	13
1 Domaine d'application	15
2 Références normatives	15
3 Termes et définitions	15
4 Généralités	15
5 Plan d'essai de CEM	16
5.1 Généralités	16
5.2 Configuration de l'EST lors des essais	16
5.3 Conditions de fonctionnement de l'EST lors des essais	16
5.4 Spécification des PERFORMANCES FONCTIONNELLES	17
5.5 Description de l'essai	17
6 Exigences relatives à l'immunité	17
6.1 Conditions lors des essais	17
6.2 Exigences pour les essais d'immunité	17
6.3 Aspects aléatoires	17
6.4 Critères de performance	17
7 Exigences relatives à l'émission	18
8 Résultats d'essai et rapport d'essai	18
9 Instructions pour l'utilisation	18
Annexe A (normative) Exigences concernant les essais d'immunité pour le MATÉRIEL D'ESSAI ET DE MESURE PORTABLE alimenté par batterie ou par le circuit mesuré	19
Annexe B (informative) Guide destiné à l'analyse et à l'évaluation de la compatibilité électromagnétique	20

COMMISSION ÉLECTROTECHNIQUE INTERNATIONALE

**MATÉRIEL ÉLECTRIQUE DE MESURE, DE COMMANDE ET DE
LABORATOIRE – EXIGENCES RELATIVES À LA CEM –****Partie 2-1: Exigences particulières –
Configurations d'essai, conditions fonctionnelles et critères
de performance pour essai de sensibilité et matériel de mesure
pour les applications non protégées de la CEM**

AVANT-PROPOS

- 1) La Commission Electrotechnique Internationale (IEC) est une organisation mondiale de normalisation composée de l'ensemble des comités électrotechniques nationaux (Comités nationaux de l'IEC). L'IEC a pour objet de favoriser la coopération internationale pour toutes les questions de normalisation dans les domaines de l'électricité et de l'électronique. À cet effet, l'IEC – entre autres activités – publie des Normes internationales, des Spécifications techniques, des Rapports techniques, des Spécifications accessibles au public (PAS) et des Guides (ci-après dénommés "Publication(s) de l'IEC"). Leur élaboration est confiée à des comités d'études, aux travaux desquels tout Comité national intéressé par le sujet traité peut participer. Les organisations internationales, gouvernementales et non gouvernementales, en liaison avec l'IEC, participent également aux travaux. L'IEC collabore étroitement avec l'Organisation Internationale de Normalisation (ISO), selon des conditions fixées par accord entre les deux organisations.
- 2) Les décisions ou accords officiels de l'IEC concernant les questions techniques représentent, dans la mesure du possible, un accord international sur les sujets étudiés, étant donné que les Comités nationaux de l'IEC intéressés sont représentés dans chaque comité d'études.
- 3) Les Publications de l'IEC se présentent sous la forme de recommandations internationales et sont agréées comme telles par les Comités nationaux de l'IEC. Tous les efforts raisonnables sont entrepris afin que l'IEC s'assure de l'exactitude du contenu technique de ses publications; l'IEC ne peut pas être tenue responsable de l'éventuelle mauvaise utilisation ou interprétation qui en est faite par un quelconque utilisateur final.
- 4) Dans le but d'encourager l'uniformité internationale, les Comités nationaux de l'IEC s'engagent, dans toute la mesure possible, à appliquer de façon transparente les Publications de l'IEC dans leurs publications nationales et régionales. Toutes divergences entre toutes Publications de l'IEC et toutes publications nationales ou régionales correspondantes doivent être indiquées en termes clairs dans ces dernières.
- 5) L'IEC elle-même ne fournit aucune attestation de conformité. Des organismes de certification indépendants fournissent des services d'évaluation de conformité et, dans certains secteurs, accèdent aux marques de conformité de l'IEC. L'IEC n'est responsable d'aucun des services effectués par les organismes de certification indépendants.
- 6) Tous les utilisateurs doivent s'assurer qu'ils sont en possession de la dernière édition de cette publication.
- 7) Aucune responsabilité ne doit être imputée à l'IEC, à ses administrateurs, employés, auxiliaires ou mandataires, y compris ses experts particuliers et les membres de ses comités d'études et des Comités nationaux de l'IEC, pour tout préjudice causé en cas de dommages corporels et matériels, ou de tout autre dommage de quelque nature que ce soit, directe ou indirecte, ou pour supporter les coûts (y compris les frais de justice) et les dépenses découlant de la publication ou de l'utilisation de cette Publication de l'IEC ou de toute autre Publication de l'IEC, ou au crédit qui lui est accordé.
- 8) L'attention est attirée sur les références normatives citées dans cette publication. L'utilisation de publications référencées est obligatoire pour une application correcte de la présente publication.
- 9) L'attention est attirée sur le fait que certains des éléments de la présente Publication de l'IEC peuvent faire l'objet de droits de brevet. L'IEC ne saurait être tenue pour responsable de ne pas avoir identifié de tels droits de brevets et de ne pas avoir signalé leur existence.

La Norme internationale IEC 61326-2-1 a été établie par le sous-comité 65A: Aspects systèmes, du comité d'études 65 de l'IEC: Mesure, commande et automation dans les processus industriels.

Cette troisième édition annule et remplace la deuxième édition parue en 2012. Cette édition constitue une révision technique.

Cette édition inclut les modifications techniques majeures suivantes par rapport à la version précédente:

- Mise à jour par rapport à l'IEC 61326-1:2020.

Le texte de cette Norme internationale est issu des documents suivants:

FDIS	Rapport de vote
65A/976/FDIS	65A/987/RVD

Le rapport de vote indiqué dans le tableau ci-dessus donne toute information sur le vote ayant abouti à l'approbation de cette Norme internationale.

Ce document a été rédigé selon les Directives ISO/IEC, Partie 2.

La présente partie de l'IEC 61326 doit être utilisée conjointement avec l'IEC 61326-1:2020 et suit la même numérotation des articles, paragraphes, tableaux et figures.

Lorsqu'un paragraphe particulier de l'IEC 61326-1 n'est pas mentionné dans la présente partie, ce paragraphe s'applique pour autant qu'il soit raisonnable. Lorsque la présente norme spécifie "addition", "modification" ou "remplacement", le texte correspondant de l'IEC 61326-1 doit être adapté en conséquence.

NOTE Le système de numérotation suivant est utilisé:

- paragraphes, tableaux et figures: ceux qui sont numérotés à partir de 101 sont complémentaires à ceux de l'IEC 61326-1;
- à l'exception de celles qui sont dans un nouveau paragraphe ou de celles qui concernent des notes de l'IEC 61326-1, les notes sont numérotées à partir de 101, y compris celles des articles ou paragraphes qui sont modifiés ou remplacés;
- les annexes supplémentaires sont appelées AA, BB, etc.

Une liste de toutes les parties de la série IEC 61326, publiées sous le titre général *Matériel électrique de mesure, de commande et de laboratoire – Exigences relatives à la CEM*, peut être consultée sur le site web de l'IEC.

Le comité a décidé que le contenu de ce document ne sera pas modifié avant la date de stabilité indiquée sur le site web de l'IEC sous "<http://webstore.iec.ch>" dans les données relatives au document recherché. A cette date, le document sera

- reconduit,
- supprimé,
- remplacé par une édition révisée, ou
- amendé.

MATÉRIEL ÉLECTRIQUE DE MESURE, DE COMMANDE ET DE LABORATOIRE – EXIGENCES RELATIVES À LA CEM –

Partie 2-1: Exigences particulières – Configurations d'essai, conditions fonctionnelles et critères de performance pour essai de sensibilité et matériel de mesure pour les applications non protégées de la CEM

1 Domaine d'application

En complément au domaine d'application de l'IEC 61326-1, la présente partie de l'IEC 61326 donne des spécifications plus détaillées des configurations d'essai, des conditions fonctionnelles et des critères de performance pour les matériels avec des circuits d'essai et de mesure (internes et/ou externes au matériel) qui n'ont pas de protection CEM pour des raisons opérationnelles et/ou fonctionnelles, comme spécifié par le fabricant.

Le fabricant spécifie l'environnement auquel le produit est destiné et sélectionne les spécifications pertinentes du niveau d'essai de l'IEC 61326-1:2020.

NOTE Exemples de matériels (entre autres): oscilloscopes, analyseurs logiques, analyseurs de spectres, analyseurs de réseaux, appareils de mesure analogiques, multimètres numériques (DMM) et systèmes d'essai de carte.

2 Références normatives

Les documents suivants cités dans le texte constituent, pour tout ou partie de leur contenu, des exigences du présent document. Pour les références datées, seule l'édition citée s'applique. Pour les références non datées, la dernière édition du document de référence s'applique (y compris les éventuels amendements).

L'Article 2 de l'IEC 61326-1:2020 s'applique avec l'exception suivante:

Addition:

IEC 61326-1:2020, *Matériel électrique de mesure, de commande et de laboratoire – Exigences relatives à la CEM – Partie 1: Exigences générales*

3 Termes et définitions

Pour les besoins du présent document, les termes et définitions donnés dans l'IEC 61326-1:2020 et dans l'IEC 60050-161 s'appliquent.

L'ISO et l'IEC tiennent à jour des bases de données terminologiques destinées à être utilisées en normalisation, consultables aux adresses suivantes:

- IEC Electropedia: disponible à l'adresse <http://www.electropedia.org/>
- ISO Online browsing platform: disponible à l'adresse <http://www.iso.org/obp>

4 Généralités

L'Article 4 de l'IEC 61326-1:2020 s'applique.